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FIG. 1

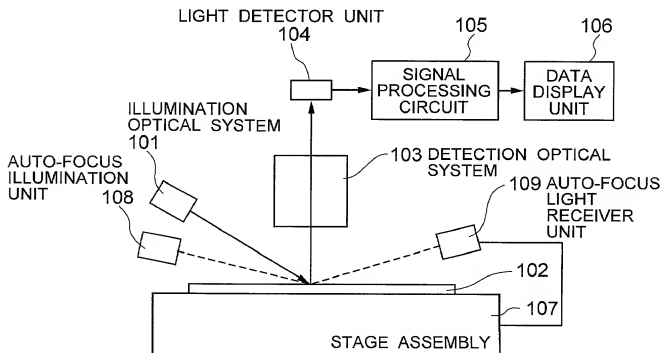
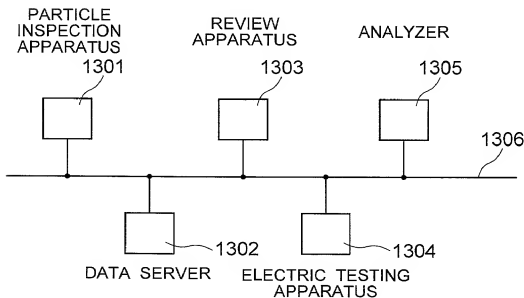


FIG. 2



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FIG. 3A

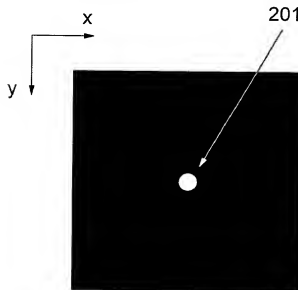


FIG. 3B

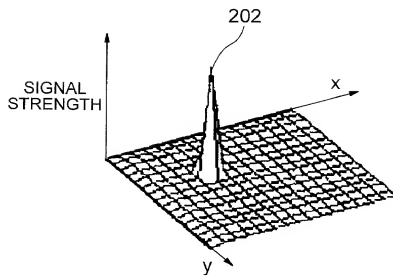


FIG. 4A

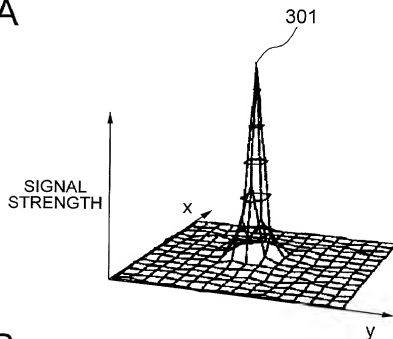


FIG. 4B

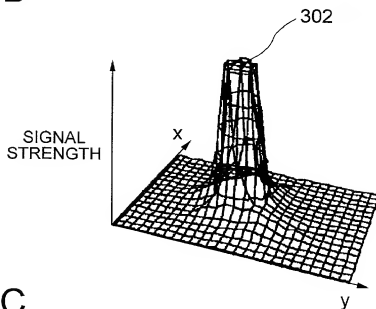


FIG. 4C

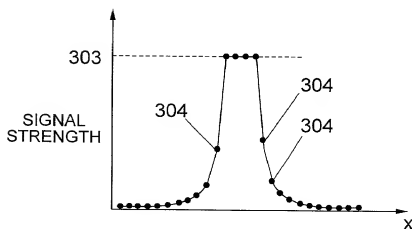


FIG. 5A

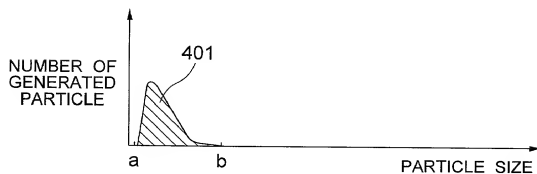


FIG. 5B

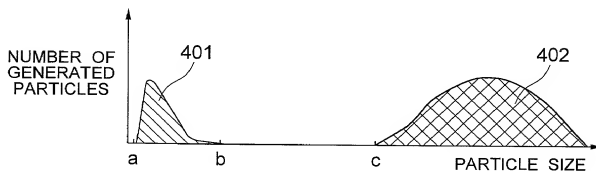
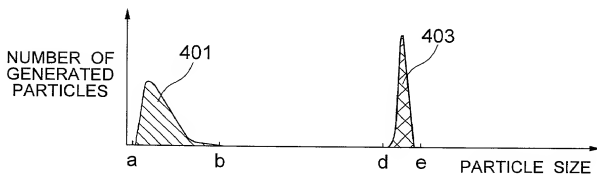


FIG. 5C



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FIG. 6

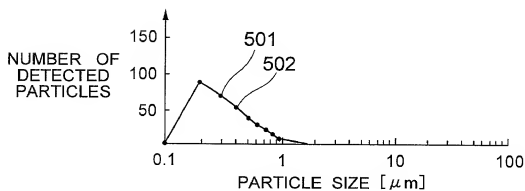


FIG. 7

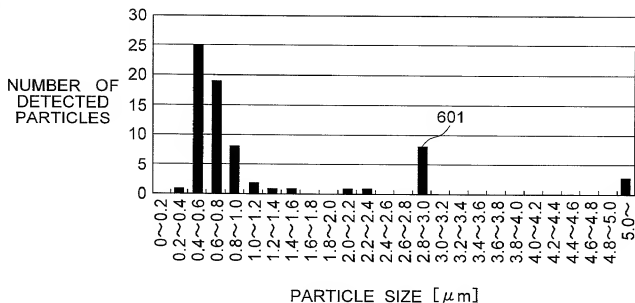


FIG. 8A

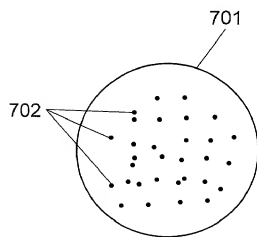
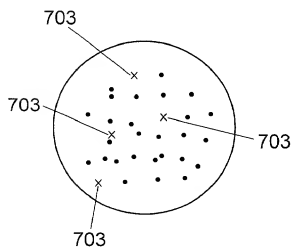


FIG. 8B



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FIG. 9A

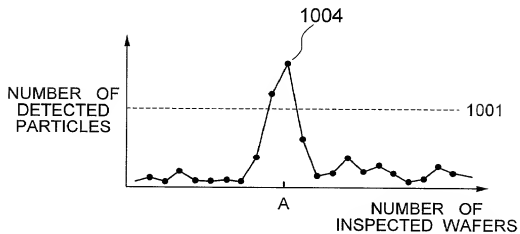


FIG. 9B

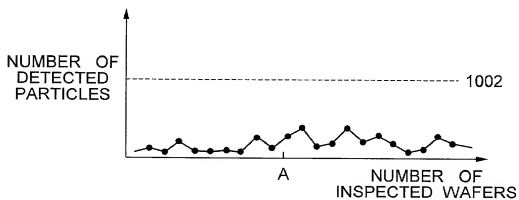
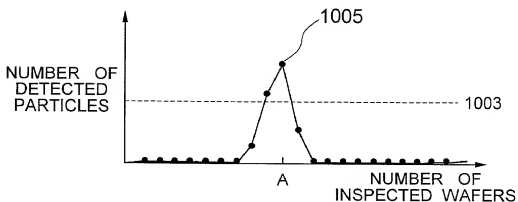


FIG. 9C



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FIG. 10

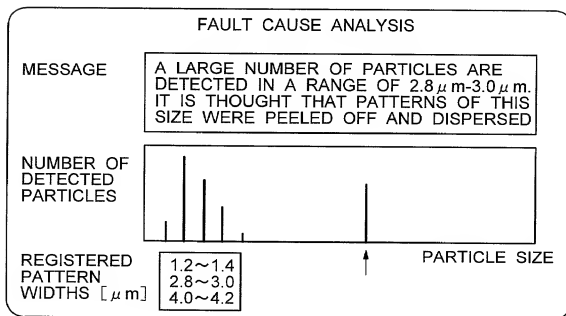
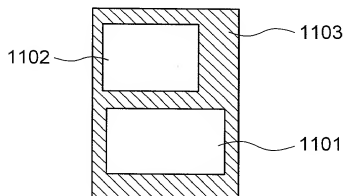


FIG. 11



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FIG. 12A

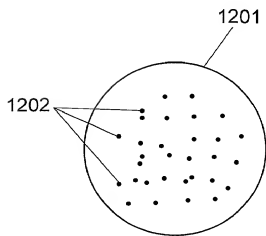


FIG. 12B

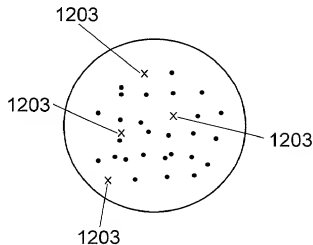
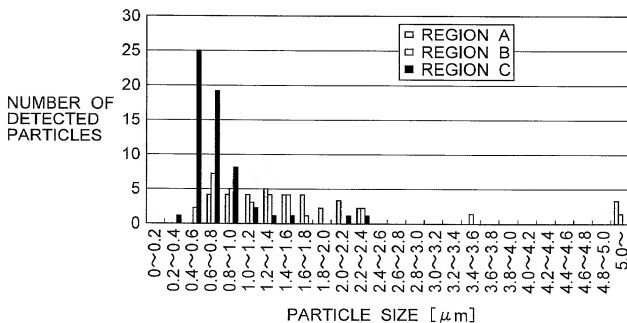


FIG. 13



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FIG. 14

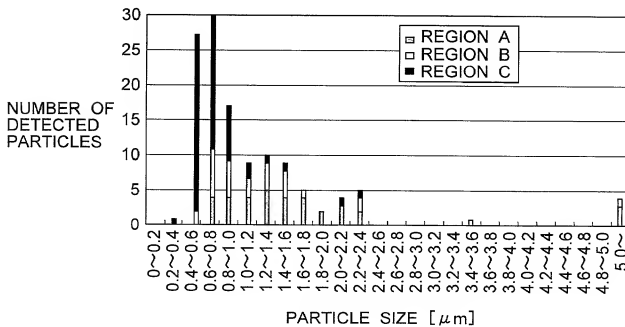


FIG. 15

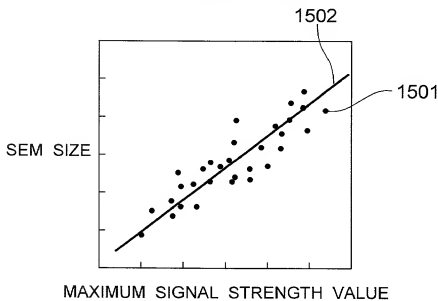


FIG. 16

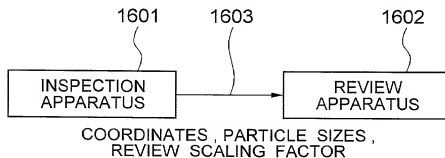


FIG. 17A

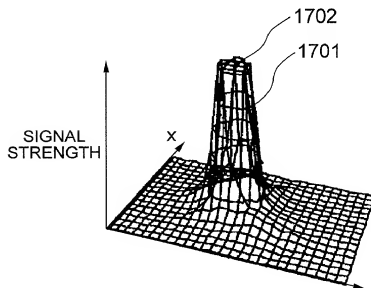


FIG. 17B

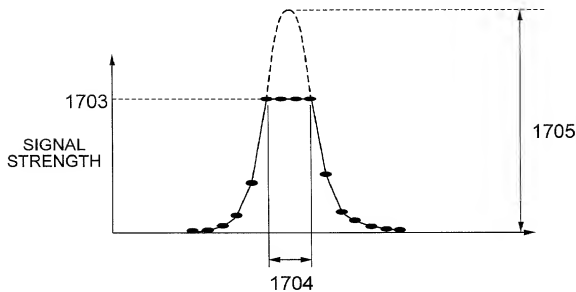
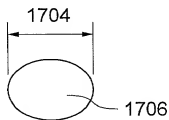


FIG. 17C



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FIG. 18A

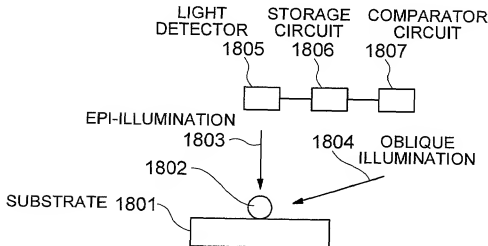
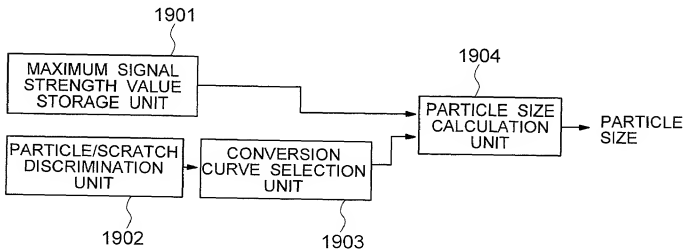


FIG. 18B

	DIFFERENCE IN SCATTERED LIGHT DEPENDING ON ILLUMINATING DIRECTION		SCATTERED LIGHT AMOUNT RATIO (EPI/OBLIQUE)
	EPI-ILLUMINATION	OBLIQUE ILLUMINATION	
PARTICLES	AMOUNT OF SCATTERED LIGHT: LARGE	AMOUNT OF SCATTERED LIGHT: LARGE	SMALL
SCRATCHES	AMOUNT OF SCATTERED LIGHT: LARGE	AMOUNT OF SCATTERED LIGHT: SMALL	LARGE

FIG. 19



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FIG. 20

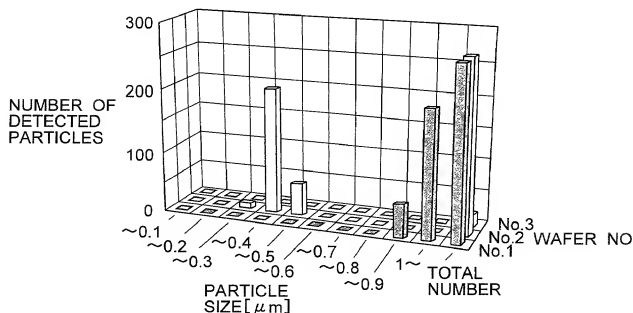


FIG. 21

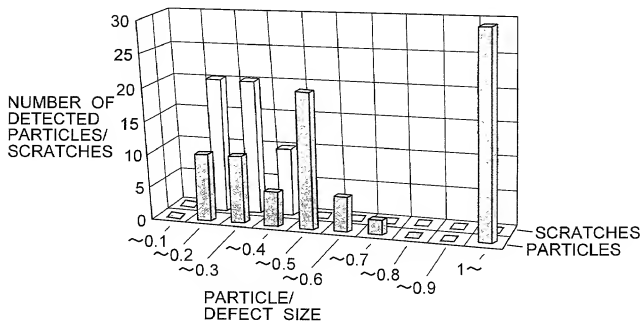


FIG. 22

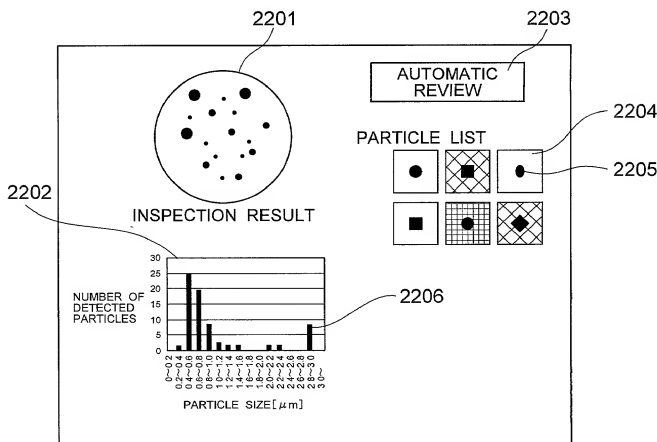
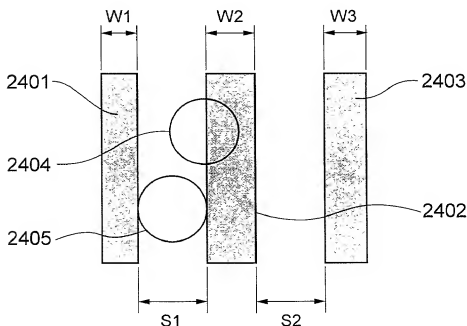


FIG. 23



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FIG. 24

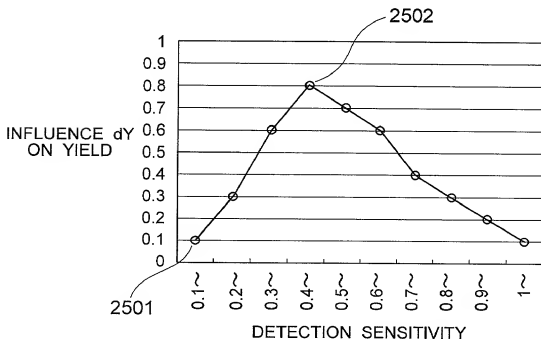
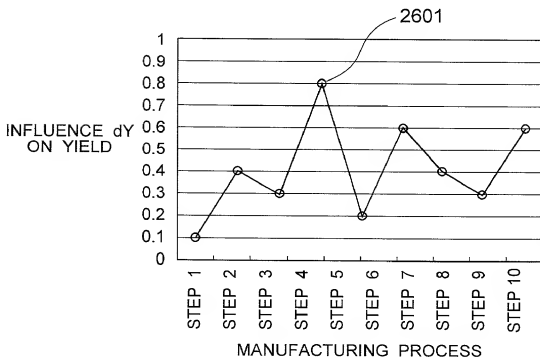


FIG. 25



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FIG. 26

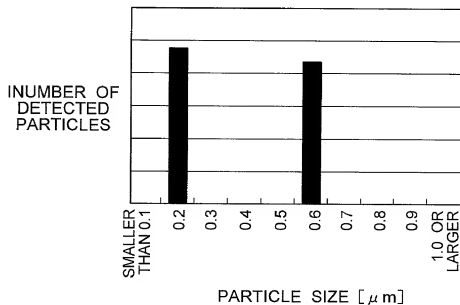
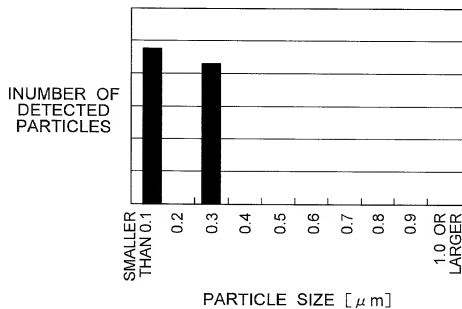


FIG. 27



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FIG. 28

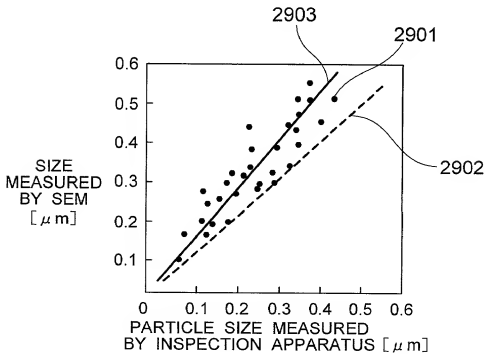
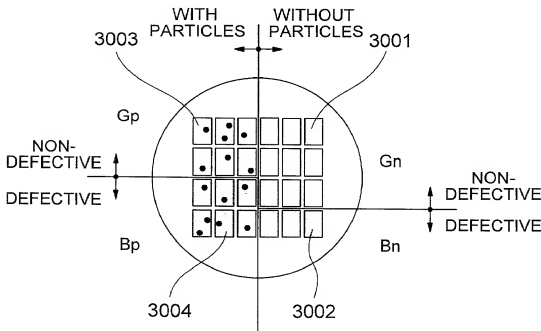


FIG. 29



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FIG. 30A

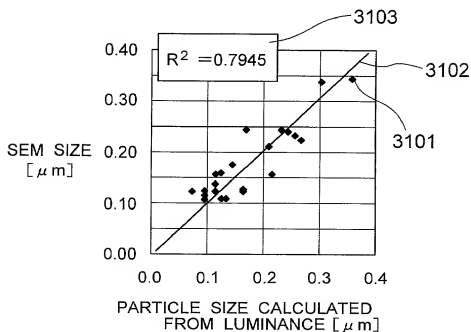
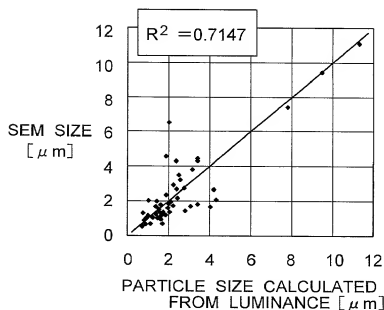


FIG. 30B



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FIG. 31

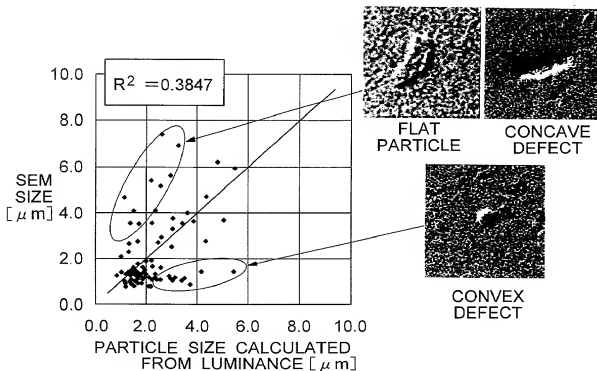
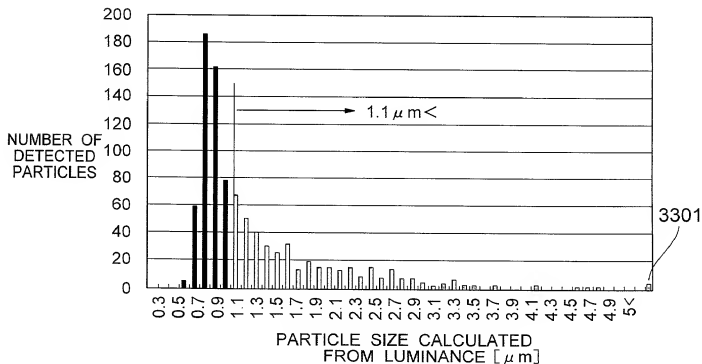


FIG. 32



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FIG. 33A

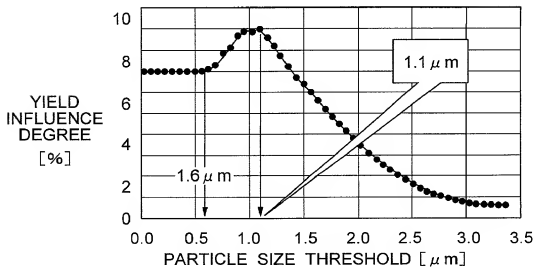


FIG. 33B

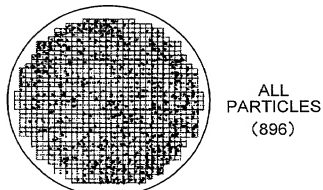


FIG. 33C

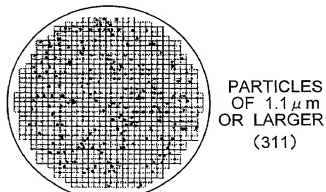


FIG. 34

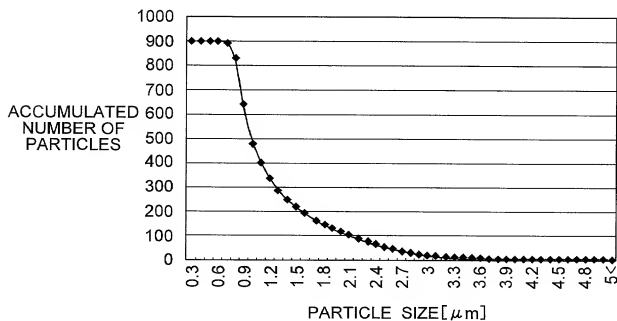


FIG. 35

